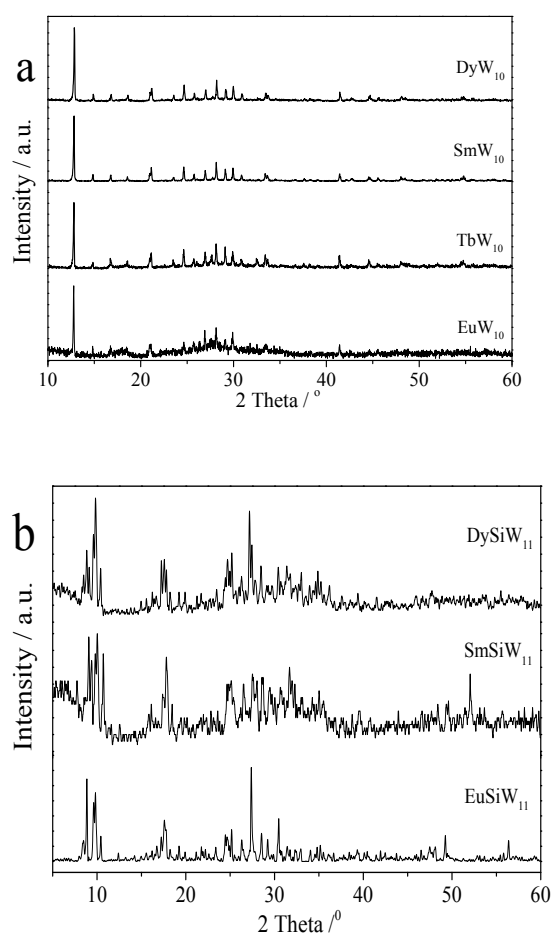


## Electronic supporting information

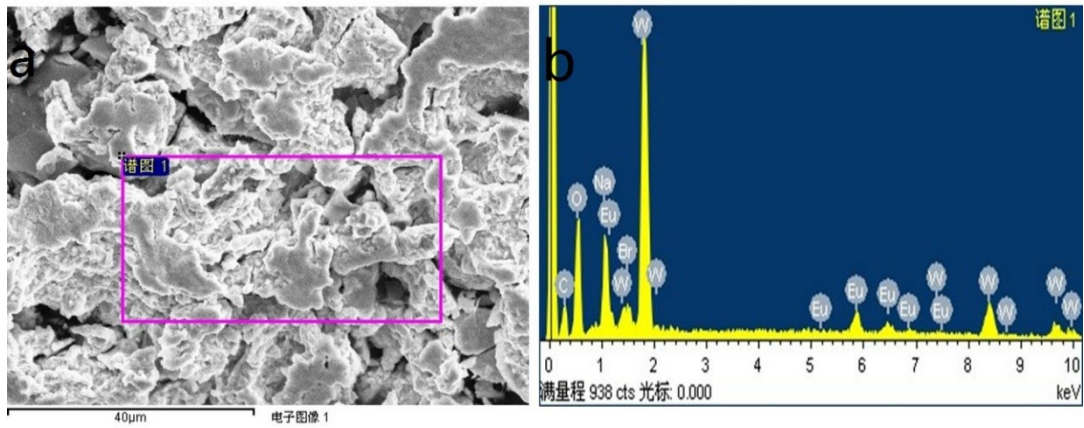
### Multicomponent hybrids with surfactant-capped lanthanide polyoxometalate and ZIF-8 to tune luminescence

Chang Liu, Bing Yan \*

Elemental analyses data: For SEuW<sub>10</sub>-ZIF-8-PEMA (%): Eu 1.80, Zn 7.15, C 45.31, H 6.45; N 6.30; for STbW<sub>10</sub>-ZIF-8-PEMA(%): Tb 1.93, Zn 7.11, C 45.02, H 6.33; N 6.26; for SSmW<sub>10</sub>-ZIF-8-PEMA (%): Sm 1.78, Zn 7.15, C 45.30, H 6.29; N 6.44; for SDyW<sub>10</sub>-ZIF-8-PEMA (%): Dy 1.95, Zn 7.10, C 44.90, H 6.27; N 6.22; for SEuSiW<sub>11</sub>-ZIF-8-PEMA (%): Eu 1.20, Zn 4.75, C 36.31, H 5.93; N 4.65; for SSmSiW<sub>11</sub>-ZIF-8-PEMA (%): Sm 1.20, Zn 4.77, C 36.45, H 5.93; N 4.59; for SDySiW<sub>11</sub>-ZIF-8-PEMA (%): Dy 1.27, Zn 4.71, C 36.03, H 5.85; N 4.45.



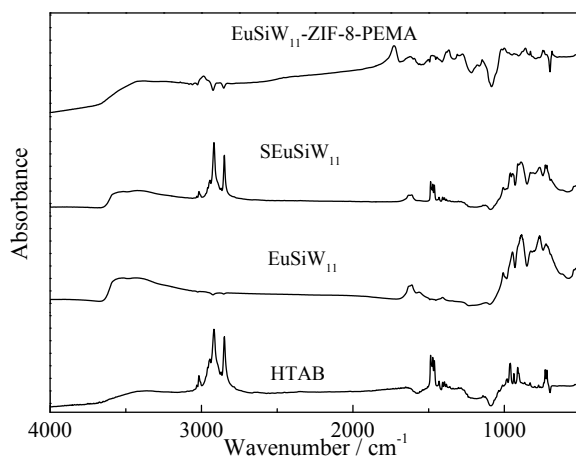
**Figure S1** X-ray diffraction patterns of Na<sub>9</sub>EuW<sub>10</sub>O<sub>36</sub>·32H<sub>2</sub>O (a), and K<sub>13</sub>Ln(SiW<sub>11</sub>O<sub>39</sub>)<sub>2</sub>·30H<sub>2</sub>O (b).



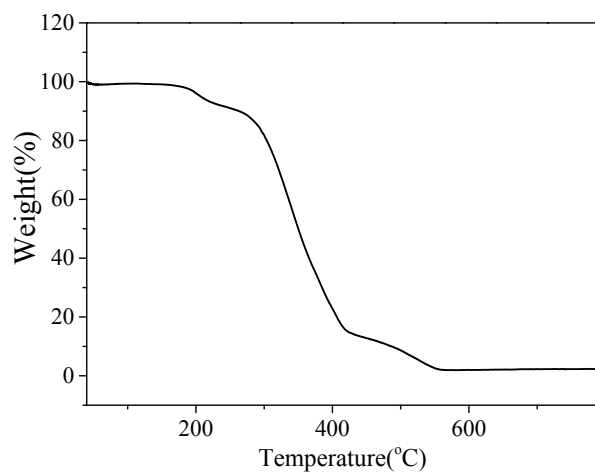
**Figure S2** The scanning electron microscope (SEM) (a) and energy dispersive spectrometer (EDS) (b) analysis of the SEuW<sub>10</sub>.

**Table S1** The weight percent and atomic percent of elements in the SEuW<sub>10</sub>.

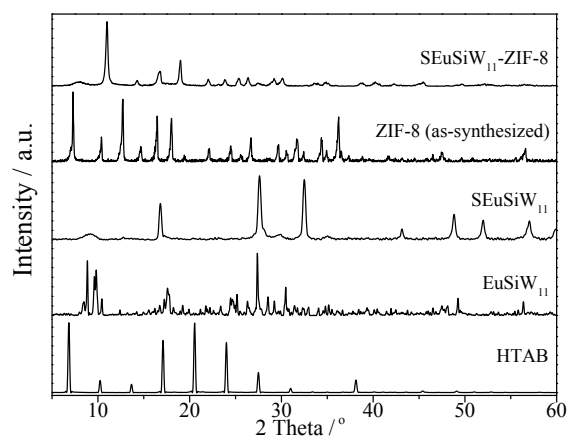
<i>element</i>	<i>weight percent</i>	<i>atomic percent</i>
C	8.00	29.28
O	16.53	45.41
Na	3.79	7.24
Br	1.44	0.79
Eu	9.57	2.77
W	60.66	14.50
total	100.00	



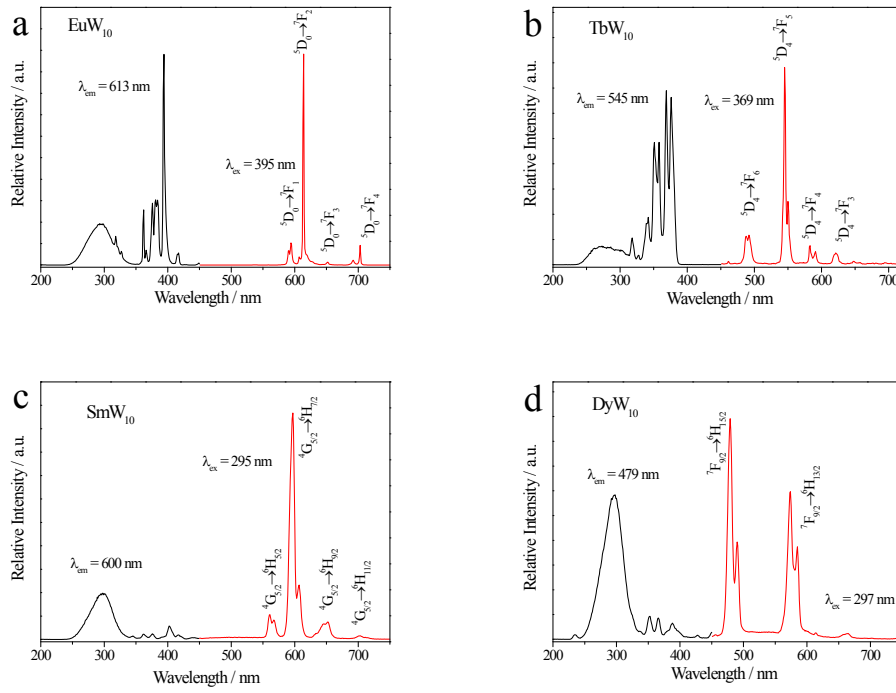
**Figure S3** Selected FTIR spectra of HTAB, EuSiW<sub>11</sub>, SEuSiW<sub>11</sub> and SEuSiW<sub>11</sub>-ZIF-8-PEMA



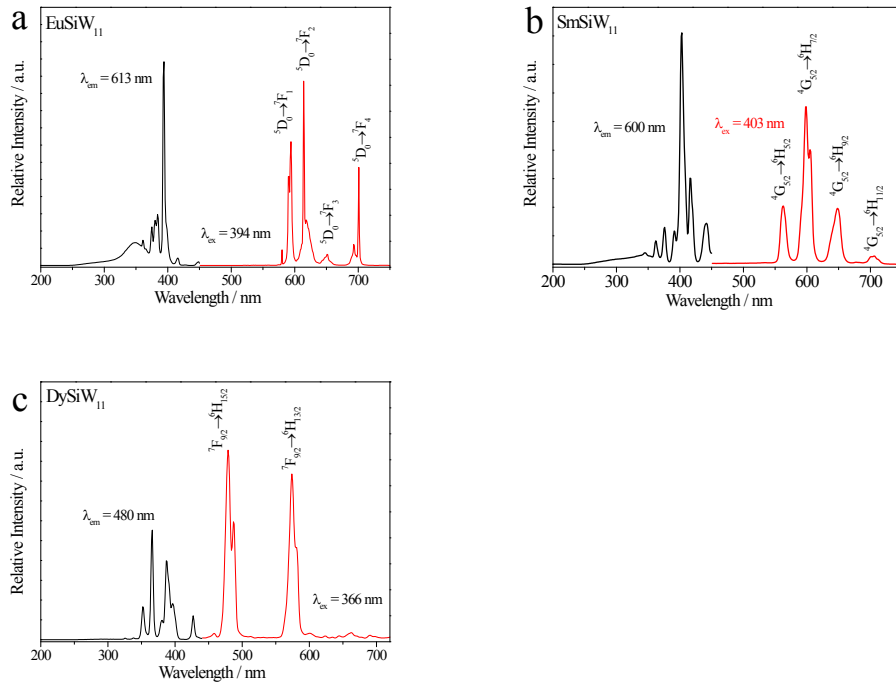
**Figure S4** TGA trace of hybrid material of SEuW<sub>10</sub>-ZIF-8-PEMA.



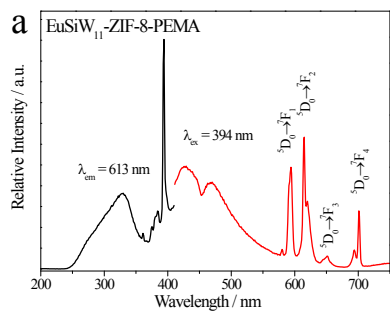
**Figure S5** Wide-angle X-ray Diffraction pattern of HTAB, EuSiW<sub>11</sub>, SEuSiW<sub>11</sub>, ZIF-8 and SEuSiW<sub>11</sub>-ZIF-8-PEMA



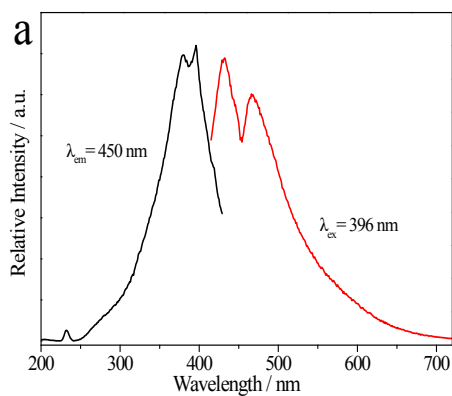
**Figure S6** The excitation and emission spectra of EuW<sub>10</sub> (a), TbW<sub>10</sub> (b), SmW<sub>10</sub> (c) and DyW<sub>10</sub> (d).



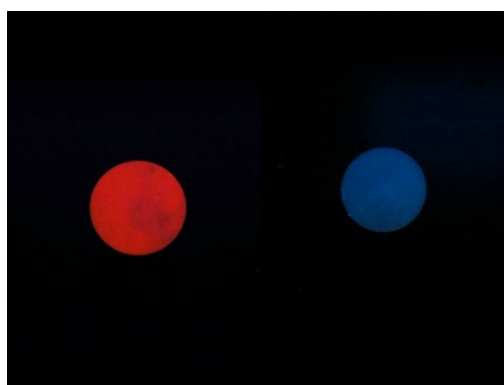
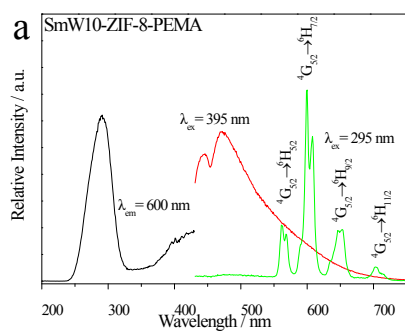
**Figure S7** The excitation and emission spectra of EuSiW<sub>11</sub> (a), SmSiW<sub>11</sub> (b) and DySiW<sub>11</sub> (c).



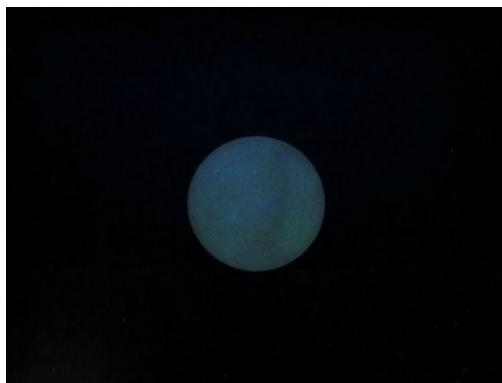
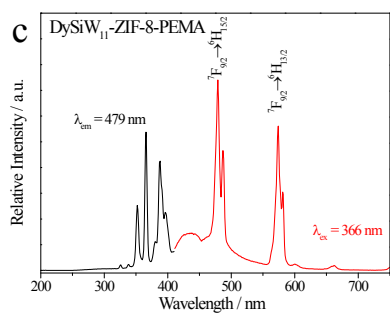
**Figure S8** The excitation and emission spectra of SeuSiW<sub>11</sub>-ZIF-8-PEMA (a) and the digital photograph of SeuSiW<sub>11</sub>-ZIF-8-PEMA by a 394 nm irradiated in dark (b).



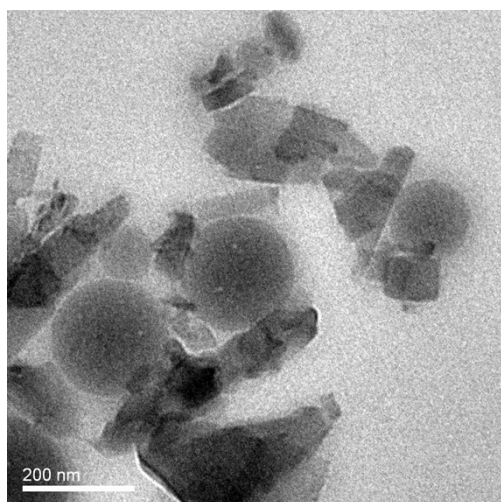
**Figure S9** The luminescent excitation and emission spectra of ZIF-8.



**Figure S10** The excitation and emission spectra of SSmW<sub>10</sub>-ZIF-8-PEMA (a), the digital photograph of SSmW<sub>10</sub>-ZIF-8-PEMA by a 295 nm irradiated (b) and 395 nm (c) in dark, respectively.



**Figure S11** The excitation and emission spectra of SDySiW<sub>11</sub>-ZIF-8-PEMA (a), the digital photograph of SDySiW<sub>11</sub>-ZIF-8-PEMA by a 366 nm irradiated (b) in dark, respectively.



**Figure S12** The transmission electron microscopy (TEM) of SEuW<sub>10</sub>-ZIF-8-PEMA.

Powder x-ray data were collected by XRD-20 diffractometer (Bruker) in reflectance mode employing Ni-filtered CuK $\alpha$  line (1.5406 Å) at 600 W (40 kV, 40 mA) power and equipped with a 2 $\theta$  detector fitted with a 0.2-mm slit. Samples were mounted on zero background sample holder. The diffraction patterns were collected by scanning powders from a wide-blade spatula. The sample surface with a razor blade. All sam

**Figure S13** Photographs of the transparent thin films, SEuW<sub>10</sub>-ZIF-8-PEMA (a) and SEuSiW<sub>11</sub>-ZIF-8-PEMA (b) respectively.